Docket No.

211897US99

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF:

Robert J. HIGGINS, et al.

SERIAL NO:

09/911,496

GAU:

2814

PADEMA

FILED:

July 25, 2001

EXAMINER: WILLE

FOR:

MONOLITHIC SEMICONDUCTOR-PIEZOELECTRIC DEVICE STRUCTURES AND ELECTRO-ACOUSTIC

CHARGE TRANSPORT DEVICES

INFORMATION DISCLOSURE STATEMENT UNDER 37 CF

ASSISTANT COMMISSIONER FOR PATENTS WASHINGTON, D.C. 20231

SIR.

Applicant(s) wish to disclose the following information.

REFERENCES

- The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references were submitted in application Serial No. 09/908,888 according to the attached copy of a Granted Petition. This application contains related subject matter.
- A check is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- ☐ A check is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

Please charge any additional fees for the papers being filed herewith and for which no check is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPJVAK, McCLELLAND, MAIER & NEUSTADT, P.C.

Richard L. Treanor

Registration No. 36,379

Tel. (703) 413-3000 Fax. (703) 413-2220 (OSMMN 03/02)

03/19/2003 CV0111 00000045 09911496

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Form PTO 1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

SERIAL NO. 211897US99

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	IST OF REFERENCES CITED BY APPLICANT				APPLICANT Robert	J. HIGGINS	Setal	, et al.		
	2003			. 2.07	FILING DATE	GROUP				
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FXA	MARER		DOCUMENT	DATE	U.S. PATENT DOCUMENTS NAME	CLASS	SUB	FILING DATE		
TN.	ITIAL		NUMBER				CLASS	IF APPROPRIATE		
		AA	3,802,967	04/09/74	Ladany et al.					
		АВ	4,174,422	11/13/79	Matthews et al.					
		AC	4,404,265	09/13/83	Manasevit					
		AD	4,482,906	11/13/84	Hovel et al.			•		
		AE	4,523,211	06/11/85	Morimoto et al.					
		AF	4,661,176	04/28/87	Manasevit					
		AG	4,793,872	12/27/88	Meunier et al.					
		АН	4,846,926	07/11/89	Kay et al.			.		
		AJ	4,855,249	08/08/89	Akasaki et al.					
		AI	4,891,091	01/02/90	Shastry					
		AK	4,912,087	03/27/90	Aslam et al.					
		AL	4,928,154	05/22/90	Umeno et al.					
		АМ	4,963,949	10/16/90	Wanlass et al.					
		AN	5,141,894	08/25/92	Bisaro et al.					
		AO	5,159,413	10/27/92	Calviello et al.					
		AP	5,173,474	12/22/92	Connell et al.					
		AQ	5,221,367	06/22/93	Chisholm et al.					
		AR	5,225,031	07/06/93	McKee et al.		1			
		AS	5,358,925	10/25/94	Neville Connell et al.					
		АТ	5,393,352	02/28/95	Summerfelt					
		AU	5,418,216	05/23/95	Fork					
		AV	5,450,812	09/19/95	McKee et al.					
		AW	5,478,653	12/26/95	Guenzer					
		AX	5,482,003	01/09/96	McKee et al.					
		AY	5,514,484	05/07/96	Nashimoto					
		AZ	5,556,463	09/17/96	Guenzer					
		ВА	5,588,995	12/31/96	Sheldon					
		вв	5,670,798	09/23/97	Schetzina					
		вс	5,733,641	03/31/98	Fork et al.		t.	-		
		BD	5,735,949	04/07/98	Mantl et al.	<u> </u>				
		BE	5,741,724	04/21/98	Ramdani et al.					
		BF	5,810,923	09/22/98	Yano et al.					
		BG	5,830,270	11/03/98	McKee et al.					
		вн	5,912,068	06/15/99	Jia					
		ВІ	6,020,222	02/01/00	Wollesen					
		BJ	6,045,626	04/04/00	Yano et al.					
		вк	6,064,078	05/16/00	Northrup et al.					
		BL	6,064,092	05/16/00	Park	1				
		вм	6,096,584	08/01/00	Ellis-Monaghan et al.		†	 		
		BN	6,103,008	08/15/00	McKee et al.	 				
		во	6,136,666	10/24/00	So	+				
		BP	6,174,755	01/16/01	Manning	 	 			
		BQ	6,180,486	01/30/01	Leobandung et al.	 				

SHEET 2 OF 23 Form PTO 1449 (Modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE SERIAL NO. ATTY DOCKET NO. 211897US99 09/911,496 **APPLICANT** LIST OF REPRENCES CITED BY APPLICANT Robert J. HIGGINS, et al. MAR 1 4 2003 FILING DATE GROUP July 25, 2001 2814

٠	25			U.S. PATENT DOCUMENTS		· · ·	
INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	CA	3,766,370	10/16/73	Walther			
	СВ	4,006,989	02/08/77	Andringa			
	CC	4,284,329	08/18/81	Smith et al.			
	CD	4,777,613	10/11/98	Shahan et al.			
	CE	4,802,182	01/31/89	Thornton et al.			
	CF	4,882,300	11/21/89	Inoue et al.			
	CG	4,896,194	01/23/90	Suzuki			•
	СН	4,999,842	03/12/91	Huang et al.			
	СІ	5,081,062	01/14/92	Vasudev et al.			
	Cl	5,155,658	10/13/92	Inam et al.			
	СК	5,248,564	09/28/93	Ramesh			
	CL	5,260,394	11/09/93	Tazaki et al.			
	СМ	5,270,298	12/14/93	Ramesh			
	CN	5,286,985	02/15/94	Taddiken			
	со	5,310,707	05/10/94	Oishi et al.			
	СР	5,326,721	07/05/94	Summerfelt			11111
	CQ	5,404,581	04/04/95	Honjo			
	CR	5,418,389	05/23/95	Watanabe]	
	cs	5,436,759	07/25/95	Dijaii et al.			
	СТ	5,576,879	11/19/96	Nashimoto			
	CU	5,606,184	02/25/97	Abrokwah, et al.			
	cv	5,640,267	06/17/97	May et al.			
*	cw	5,674,366	10/07/97	Hayashi et al.			
	СХ	5,729,641	03/17/98	Chandonnet et al.			
	CY	5,790,583	08/04/98	Но			
	CZ	5,825,799	10/20/98	Ho et al.			<u></u>
	DA	5,857,049	01/05/99	Beranek et al.			
	DВ	5,874,860	02/23/99	Brunel et al.			
	DC	5,926,496	07/20/99	Ho et al.			
	DD	5,937,285	08/10/99	Abrokwah, et al.			
	DE	5,981,400	11/09/99	Lo			
	DF	5,990,495	11/23/99	Ohba			
	DG	6,002,375	12/14/99	Corman et al.			
	DН	6,008,762	12/28/99	Nghiem			.
	DI	6,055,179	04/25/00	Koganei et al.			
	DJ	6,107,653	08/22/00	Fitzgerald			
	DK	6,113,690	09/05/00	Yu et al.			
	DL	6,114,996	09/05/00	Nghiem			
	DΜ	6,121,642	09/19/00	Newns			
	DN	6,128,178	10/03/00	Newns			
	DO	6,143,072	11/07/00	McKee et al.			
	DP	6,184,144	02/06/01	Lo			
	DQ	6,222,654	04/24/01	Frigo	 		

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XAMINER		DOCUMENT	DATE	NAME	CLASS	SUB	FILING DATE
VITIAL	EA	NUMBER 4,484,332	11/20/84	Hawrylo	 	CLASS	IF APPROPRIATE
	EB	4,815,084	03/21/89	Scifres et al.			
	EC	4,876,219	10/24/89	Eshita et al.		 	
	ED	4,963,508	10/16/90	Umeno et al.		 	
	EE	5,060,031	10/22/91	Abrokwah, et al.	ļ		
	EF	5,063,166	11/05/91	Mooney et al.			
	EG	5,116,461	05/26/92	Lebby et al.	ļ		
	EH	5,127,067	06/30/92	Delcoco et al.		-	
	EI		09/01/92	Ma	ļ	 	
	EJ	5,144,409	03/08/94	Chapple-Sokol et al	ļ	 	-
		5,293,050	10/18/94	Calviello et al.	ļ	 	
_	EK	5,356,831	02/21/95		ļ <u>.</u>	 	
	EL	5,391,515		Kao et al.		ļ	
	EM	5,442,191	08/15/95	Ma		4	
	EN	5,444,016	08/22/95	Abrokwah, et al.		<u> </u>	
	EO	5,480,829	01/02/96	Abrokwah, et al.	ļ	ļ	
	EP	5,528,414	06/18/96	Oakley	ļ	ļ	
	EQ	5,614,739	03/25/97	Abrokwah et al.			
	ER	5,729,394	03/17/98	Sevier et al.	<u> </u>	<u> </u>	
	ES	5,731,220	03/24/98	Tsu et al.			
	ET	5,764,676	06/09/98	Paoli et al.			
	ΕŲ	5,777,762	07/07/98	Yamamoto			
	EV	5,778,018	07/07/98	Yoshikawa et al.			
	EW	5,778,116	07/07/98	Tomich			
	EX	5,801,105	09/01/98	Yano et al.			
	EY	5,828,080	10/27/98	Yano et al.			
	EZ	5,858,814	01/12/99	Goossen et al.			
	FA	5,861,966	01/19/99	Ortel			
	FB	5,883,996	03/16/99	Knapp et al.			
	FC	5,995,359	11/30/99	Klee et al.			
	FD	6,058,131	05/02/00	Pan			
	FE	6,137,603	10/24/00	Henmi			
	FF	6,146,906	11/14/00	Inoue et al.			
	FG	6,173,474	01/16/01	Conrad			
	FH	6,180,252	01/30/01	Farrell et al.			
	FI	4,242,595	12/30/0	Lehovec			
	FJ	4,398,342	08/16/83	Pitt et al.			
	FK	4,424,589	01/03/84	Thomas et al.			
	FL	4,876,208	10/24/89	Gustafson et al.	1		
	FM	4,482,422	11/84	McGinn et al.		1	
	FN	4,667,088	05/19/87	Kramer		1	
	FO	4,772,929	09/20/88	Manchester et al.	1	1	
	FP	4,841,775	06/27/89	lkeda et al.		1	
	FQ	4,845,044	07/04/89	Ariyoshi et al.	 	 	

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				U.S. PATENT DOCUMENTS			
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	GA	4,868,376	09/19/89	Lessin et al.			
	GB	4,885,376	12/05/89	Verkade			
	GC	4,888,202	12/89	Murakami et al.			
	GD	4,891,091	12/90	Waniass et al.			
	GE	5,051,790	09/24/91	Hammer			
	GF	5,055,445	10/08/91	Belt et al.			
	GG	5,081,519	11/14/92	Nishimura et al.			
	GН	5,143,854	09/01/92	Pirrung et al.			
	GI	5,185,589	02/09/93	Krishnaswamy et al.			
	GJ	5,191,625	03/02/93	Gustavsson			
	GK	5,194,397	03/16/93	Cook et al.			
	GL	5,208,182	05/04/93	Narayan et al.			
	GМ	5,216,729	06/01/93	Berger et al.	1		
•	GN	5,314,547	05/24/94	Heremans et al.			
	GO	5,352,926	10/04/94	Andrews			
	GP	5,356,509	10/18/94	Terranova et al.			
	GQ	5,371,734	12/06/94	Fischer			
	GR	5,372,992	12/94	Itozaki et al.	1		
	GS	5,405,802	04/11/95	Yamagata et al.			
	GT	5,442,561	08/15/95	Yoshizawa et al.			
	GU	5,453,727	09/26/95	Shibasaki et al.			
	G۷	5,466,631	11/14/95	Ichikawa et al.	1		
	GW	5,473,047	12/05/95	Shi			
	GX	5,473,171	12/95	Summerfelt			
	GY	5,479,033	12/26/95	Baca et al.			
	GZ	5,486,406	01/23/96	Shi		İ	
	НА	5,491,461	02/13/96	Partin et al.	1		
	нв	5,492,859	02/20/96	Sakaguchi et al.			
	нс	5,494,711	02/27/96	Takeda et al.			
	HD	5,504,035	04/02/96	Rostoker et al.			
	HE	5,504,183	04/02/96	Shi			
	HF	5,511,238	04/23/96	Bayraktaroglu	-		
•	НG	5,512,773	04/96	Wolf et al.			
	нн	5,515,047	05/07/96	Yamakido et al.			
	н	5,515,810	05/14/96	Yamashita et al.			
	HJ	5,519,235	05/96	Ramesh	1		
	нк	5,549,977	08/96	Jin et al.	1		
	HL	5,551,238	09/03/96	Prueitt	1		
	нм	5,552,547	09/03/96	Shi	1		
	HN	5,589,284	12/31/96	Summerfelt et al.	1		
	но	5,602,418	02/11/97	lmai et al.	1		
	HP	5,633,724	05/27/97	King et al.			

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Robert J. HIGGINS, et al. GROUP

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XAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
-	IA	5,650,646	07/22/97	Summerfelt			
	IB	5,656,382	08/12/97	Nashimoto			
	IC_	5,659,180	08/19/97	Shen et al.			
	ID	5,661,112	08/26/97	Hatta et al.			
	ΙE	5,679,965	11/95	Schetzina			
	IF	5,725,641	03/10/98	MacLeod			
	IG	5,745,631	04/28/98	Reinker .			
	iΗ	5,776,621	07/07/98	Nashimoto			
	Ш	5,777,350	07/07/98	Nakamura et al.			
	IJ	5,789,845	08/04/98	Wadaka et al.			
	ΙK	5,792,569	08/11/98	Sun et al.			
	IL	5,792,679	08/11/98	Nakato			
	М	5,796,648	08/18/98	Kawakubo et al.		ĺ	
	IN	5,801,072	09/01/98	Barber		Ì	
	10	5,812,272	09/22/98	King et al.			
	IP	5,814,583	09/98	Itozaki et al.			
	IQ	5,825,055	10/20/98	Summerfelt			
	IR	5,827,755	10/27/98	Yonchara et al.			
	is	5,833,603	11/10/98	Kovacs et al.		Ì	
	ΙΤ	5,838,035	11/17/98	Ramesh			
	IU	5,844,260	12/01/98	Ohori			
	IV	5,846,846	12/08/98	Suh et al.			
	iw	5,863,326	01/26/99	Nause et al.			
	IX	5,872,493	02/16/99	Ella			
	ΙΥ	5,879,956	03/99	Seon et al.			
	ΙZ	5,880,452	03/09/99	Plesko			
	JA	5,883,564	03/16/99	Partin			
	ЈВ	5,907,792	05/25/99	Droopad et al.			
	ηC	5,937,274	08/10/99	Kondow et al.	<u> </u>		
	ΊD	5,948,161	09/07/99	Kizuki		ii	
	JΕ	5,959,879	09/28/99	Koo			, , , , , , , , , , , , , , , , , , , ,
-	JF	5,966,323	10/99	Chen et al.			
	JG	5,987,011	11/16/99	Toh			
	JН	6,022,140	02/08/00	Fraden et al.			
	λı	6,022,410	02/08/00	Yu et al.			
	JJ	6,023,082	02/08/00	McKee et al.			
	JК	6,028,853	02/22/00	Haartsen			
	JL	6,049,702	04/11/00	Tham et al.			. <u> </u>
	JМ	6,078,717	06/20/00	Nashimoto et al			
	JN	6,088,216	07/00	Laibowitz et al.			
 	10	6,090,659	07/00	Laibowitz et al.	1		
	JΡ	6,107,721	08/22/00	Lakin	1		
	JQ	6,153,010	11/28/00	Kiyoku et al			

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	KA	6,153,454	11/28/00	Krivokapic				
	кв	6,191,011	02/01	Gilboa et al			- · · · · · · · · · · · · · · · · · · ·	
	кс	6,204,737	03/20/01	Ella				
	KD	6,224,669	05/01/01	Yi et al.			**************************************	
	KE	6,225,051	05/01/01	Sugiyama et al.			_	
	KF	6,241,821	06/05/01	Yu et al.			, ***	
	KG	6,265,749	07/24/01	Gardner et al.				
	кн	6,313,486	11/01	Kencke et al.				
	KI	6,316,832	11/13/01	Tsuzuki et al.				
-	KJ	2002/0008234	01/02	Emrick				
	KK	3,670,213	06/13/72	Nakawaga et al.				
	KL	4,756,007	07/05/88	Qureshi et al.				
	км	4,773,063	09/20/88	Hunsperger et al.			-	
	KN	5,394,489	02/28/95	Koch				
	ко	5,406,202	04/11/95	Mehrgardt et al.				
	KP	5,528,067	06/18/96	Farb et al.				
	ΚQ	5,572,052	11/05/96	Kashihara et al.				
	KR	5,767,543	06/16/98	Ooms et al.				
	KS	6,175,497	01/16/01	Tseng et al.			# 0 # 0 · · · · · · · · · · · · · · · ·	
	KT	6,197,503	03/06/01	Vo-Dinh et al.				
	ΚÜ	6,248,459	06/19/01	Wang et al.				
	ΚV	6,252,261	06/26/01	Usui et al.				
	ĸw	6,255,198	07/03/01	Linthicum et al.				
	кх	6,268,269	07/31/01	Lee et al.				
	KY	6,291,319	09/18/01	Yu et al.				
	ΚZ	6,316,785	11/13/01	Nunoue et al.				
	LA	6,343,171	01/29/02	Yoshimura et al.				
	LB	4,965,649	10/23/90	Zanio et al.				
	LC	6,253,649	05/01	Kawahara et al.				
-	LD	6,211,096	04/01	Allman et al.				
	LE	6,239,449	05/29/01	Fafard et al.				
	LF	2001/0013313	08/16/01	Droopad et al.				
	LG	6,184,044	02/06/01	Sone et al.				
	LH	6,011,646	01/04/00	Mirkarimi et al.				
	LI	5,227,196	07/13/93	Itoh				
-	LJ	6,150,239	11/21/00	Goesele et al.				
	LK	5,441,577	08/15/95	Sasaki et al.	- 	 		
	LL	4,459,325	07/10/84	Nozawa et al.				
	LM	4,392,297	07/12/83	Little				
	LN	4,289,920	09/15/81	Hovel	 	 		
	LO	5,281,834	01/25/94	Cambou et al.		 		
	LP	4,901,133	02/13/90	Curran et al.				
	LQ	5,514,904	05/07/96	Onga et al.	- 	 		

MAR 1 4 2003 Form PTO 1449 (Modified) (Modified)

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	МВ	5,528,057	06/18/96	Yanagase et al.			
	МС	6,229,159	05/08/01	Suzuki			
	MD	4,748,485	05/31/88	Vasudev			
	ME	4,984,043	01/08/91	Vinal			
-	MF	5,754,319	05/19/98	Van De Voorde et al.			
	MG	6,108,125	08/22/00	Yano			
·	МН	5,073,981	12/17/91	Giles et al.			
	МІ	5,140,651	08/18/92	Soref et al.			
	MJ	5,610,744	03/11/97	Ho et al.			
	мк	6,362,017	03/26/02	Manabe et al.			****
	ML	6,242,686	06/05/01	Kishimoto et al.			•
	ММ	5,689,123	11/18/97	Major et al.			
	MN	5,670,800	09/23/97	Nakao et al.			
	МО	5,067,809	11/26/91	Tsubota			
	MP	5,596,205	01/21/97	Reedy et al.			
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	MS	4,084,130	04/11/78	Holton			
	МТ	6,093,302	07/25/00	Montgomery			
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	NP	6,011,641	01/04/00	Shin et al.			
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	ОВ	4,681,982	07/21/87	Yoshida			
	ОС	4,629,821	12/16/86	Bronstein-Bonte et al.			
	QO	4,452,720	06/05/84	Harada et al.		`	
	OE	3,935,031	01/27/76	Adler			
	OF	5,760,426	06/02/98	Marx et al.			
	OG	5,053,835	10/01/91	Horikawa et al.			
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	01	5,770,887	06/23/98	Tadatomo et al.			
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	ок	4,774,205	09/27/88	Choi et al.			
	OL	6,359,330 B1	03/19/02	Goudard			
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	ON	5,734,672	03/31/98	McMinn et al.			
	00	6,367,699 B2	04/09/02	Ackley			
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	PK	6,427,066	07/30/02	Grube			
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	QG	6,039,803	03/21/00	Fitzgerald et al.				
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	QL	4,594,000	06/10/86	Falk et al.				
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	QV	4,910,164	03/20/90	Shichijo				
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	QX	6,121,647	09/19/00	Yano et al.				
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	RA	6,410,941	06/25/02	Taylor et al.				
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	RK	5,977,567	11/02/99	Verdiell				
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•	UG	6,013,553	01/11/00	Wallace et al.			
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	AAB	0 342 937	11/23/89	EP	×		
	AAC	0 455 526	06/11/91	EP	×		
	AAD	0 602 568	06/22/94	EP	×		
	AAE	0 607 435	07/27/94	EP	×		
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	ABC	WO 99/19546	04/22/99	WIPO			
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	ABG	GB 2 335 792	09/29/99	Great Britain			
	АВН	1 109 212	06/20/01	Europe			
	ABI	DE 197 12 496	10/30/97	Germany		×	
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	BAD	WO 98/05807	01/12/98	WIPO		
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SHEET 14 OF 23 U.S. DEPARTMENT OF CUIVING Form PTO 1449 U.S. DEPARTMENT OF COMMERCE ATTY DOCKET NO. SERIAL NO. MAR 1 4 2003 211897US99 09/911,496 **APPLICANT** LIST OF REPRENCES CITED BY APPLICANT Robert J. HIGGINS, et al. FILING DATE **GROUP** MADEMAN July 25, 2001 2814 **FOREIGN PATENT DOCUMENTS** DOCUMENT DATE COUNTRY TRANSLATION NUMBER YE\$ NO CAA 52-89070 07/26/77 Japan CAB EP 1 069 606 01/17/01 Europe CAC WO 02/03113 01/10/02 WIPO CAD WIPO 01/10/02 WO 02/03467 CAE 0 630 057 12/21/94 EUROPE CAF 61-36981 02/21/86 Japan w/English Abstract CAG WO 93/07647 04/15/93 WIPO CAH 2002-9366 01/11/02 Japan w/English Abstract EP 0 881 669 12/02/98 CAI Europe CAJ WO 02/03480 01/10/02 WIPO CAK WO 02/50879 06/27/02 WIPO EP 0 777 379 CAL 06/04/97 Europe WIPO WO 01/04943 A1 01/18/01 CAM XX CAN WO 02/47127 A2 06/13/02 WIPO JP 58-075868 05/07/83 Japan w/English Abstract CAO CAP EP 0 993 027 . 04/12/00 Europe CAQ EP 0 711 853 05/15/96 Europe CAR WO 98/20606 05/14/98 WIPO CAS EP 1 043 765 10/11/00 Europe CAT 0 300 499 01/25/89 Europe CAU EP 1 085 319 03/21/01 Europe 03/08/01 WIPO CAV WO 01/16395 CAW 2000-351692 12/19/00 Japan w/English Abstract CAX 03-188619 08/16/91 Japan (English Abstract only) CAY 63-289812 11/28/88 Japan (English Abstract only) CAZ EP 0 884 767 12/16/98 Europe CBA 06-069490 03/11/94 Japan (English Abstract only) CBB WO 01/59821 A1 08/16/01 WIPO CBC CBD CBE CBF CBG СВН CBI CBJ CBK CBL СВМ CBN

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